

WHAT IS CLAIMED IS:

1. A test apparatus used for evaluating a multilayer wiring board formed by successively stacking layers, comprising:

a prove part configured to be connected to an incomplete multilayer wiring board that is in a half finished state before completion; and

a supplementary part supplementing an element of the multilayer wiring board, said incomplete multilayer wiring board lacking said element.

2. The test apparatus as claimed in claim 1, wherein the supplementary part includes layer wiring of the multilayer wiring board, said incomplete multilayer wiring board lacking said layer wiring.